

Lianhua Jin

List of Publications by Year in descending order

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72
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72
times ranked

212
citing authors

| # | ARTICLE | IF | CITATIONS |
|----|---|-----|-----------|
| 1 | Shadow moiré profilometry using the phase-shifting method. <i>Optical Engineering</i> , 2000, 39, 2119. | 1.0 | 55 |
| 2 | Measurement of Dispersion of Effective Electro-Optic Coefficients $r_{13}^{(E)}$ and $r_{33}^{(E)}$ of Non-Doped Congruent LiNbO_3 Crystal. <i>Japanese Journal of Applied Physics</i> , 2008, 47, 5503. | 1.5 | 28 |
| 3 | Si/SiO ₂ Core/Shell Luminescent Silicon Nanocrystals and Porous Silicon Powders With High Quantum Yield, Long Lifetime, and Good Stability. <i>Frontiers in Physics</i> , 2019, 7, . | 2.1 | 22 |
| 4 | Shadow moiré profilometry by frequency sweeping. <i>Optical Engineering</i> , 2001, 40, 1383. | 1.0 | 19 |
| 5 | Measurement of characteristics of magnetic fluid by the Mueller matrix imaging polarimeter. <i>Optical Engineering</i> , 2004, 43, 181. | 1.0 | 15 |
| 6 | Measurement of Wavelength Dependence of Electro-Optic Coefficients r_{22} of Non-doped and 5% MgO-doped Congruent LiNbO_3 Crystals and 1.8% MgO-doped Quasi-stoichiometric LiNbO_3 Crystal by Multiple Reflection Interference Method. <i>Optical Review</i> , 2007, 14, 194-200. | 2.0 | 15 |
| 7 | Polarization properties of scattered light from macrorough surfaces. <i>Optics Letters</i> , 2010, 35, 595. | 3.3 | 13 |
| 8 | Rotatable Offner imaging system for ellipsometric measurement. <i>Review of Scientific Instruments</i> , 2017, 88, 013704. | 1.3 | 11 |
| 9 | Measurement of diameter of cylindrical openings using a disk beam probe. <i>Optical Review</i> , 2018, 25, 656-662. | 2.0 | 11 |
| 10 | Copper deposition in microporous silicon using supercritical fluid. <i>Thin Solid Films</i> , 2014, 567, 82-86. | 1.8 | 10 |
| 11 | In situ imaging ellipsometer using a LiNbO_3 electrooptic crystal. <i>Thin Solid Films</i> , 2014, 571, 532-537. | 1.8 | 10 |
| 12 | Extracting calibrated parameters from imaging ellipsometric measurement. <i>Japanese Journal of Applied Physics</i> , 2017, 56, 116602. | 1.5 | 10 |
| 13 | Fast and Simultaneous Measurement of Both Birefringence and Azimuth Angle Using y -Cut LiNbO_3 Phase Modulator. <i>Japanese Journal of Applied Physics</i> , 2006, 45, 5244-5247. | 1.5 | 9 |
| 14 | Direct Electropolymerization of Poly(para-phenylene)vinylene Films on Si and Porous Si. <i>Journal of the Electrochemical Society</i> , 2010, 157, H534. | 2.9 | 7 |
| 15 | Fast Imaging Ellipsometer Using a LiNbO_3 Electrooptic Crystal. <i>Japanese Journal of Applied Physics</i> , 2013, 52, 036702. | 1.5 | 7 |
| 16 | Supercritical fluid deposition of copper into mesoporous silicon. <i>Thin Solid Films</i> , 2013, 545, 357-360. | 1.8 | 7 |
| 17 | General window correction method for ellipsometry measurements. <i>Optics Express</i> , 2014, 22, 27811. | 3.4 | 7 |
| 18 | Temperature characteristics of a Y-cut Z-propagation LiNbO_3 light modulator for application to polarimeters. <i>Optical Review</i> , 2010, 17, 30-40. | 2.0 | 6 |

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|----|---|-----|-----------|
| 19 | Electro-optic modulation analysis of a Y-cut Z-propagation LiNbO ₃ light modulator: Comparison with an X-cut Z-propagation LiNbO ₃ light modulator and a dual LiNbO ₃ crystal type modulator. <i>Optical Review</i> , 2011, 18, 203-211. | 2.0 | 6 |
| 20 | Polarization characteristics of scattered light from macroscopically rough surfaces. <i>Optical Review</i> , 2015, 22, 511-520. | 2.0 | 6 |
| 21 | In situ ellipsometry of Cu surfaces immersed in benzotriazole-hydrogen peroxide solutions. <i>Japanese Journal of Applied Physics</i> , 2016, 55, 06JG03. | 1.5 | 6 |
| 22 | Measurement of Optical Constants of Wet Porous Silicon Using In Situ Photoconduction. <i>ECS Journal of Solid State Science and Technology</i> , 2016, 5, P190-P196. | 1.8 | 6 |
| 23 | Multi-Wavelength Mueller Matrix Polarimeter. <i>Optical Review</i> , 2005, 12, 281-286. | 2.0 | 5 |
| 24 | Lateral ellipsometry resolution for imaging ellipsometry measurement. <i>Japanese Journal of Applied Physics</i> , 2021, 60, 058003. | 1.5 | 5 |
| 25 | Calibration of the retardation inhomogeneity for the compensator-rotating imaging ellipsometer. <i>Applied Optics</i> , 2019, 58, 9224. | 1.8 | 5 |
| 26 | <i>In-situ</i> Spectroscopic Ellipsometry of the Cu Deposition Process from Supercritical Fluids: Evidence of an Abnormal Surface Layer Formation. <i>Japanese Journal of Applied Physics</i> , 2012, 51, 05EA02. | 1.5 | 5 |
| 27 | Stokes parameters of reflected and scattered light by a rough surface. <i>Proceedings of SPIE</i> , 2009, , , . | 0.8 | 4 |
| 28 | Electropolymerization of Poly(para-phenylene)vinylene Films onto and Inside Porous Si layers of Different Types and Morphologies. <i>Journal of the Electrochemical Society</i> , 2010, 157, D648. | 2.9 | 4 |
| 29 | Electro-Optic Coefficient r_{51} of LiNbO ₃ Crystal Obtained from Measurement of Retardation Induced by Square of Electric Field. <i>Japanese Journal of Applied Physics</i> , 2013, 52, 058001. | 1.5 | 4 |
| 30 | Correction of large birefringent effect of windows for in situ ellipsometry measurements. <i>Optics Letters</i> , 2014, 39, 1549. | 3.3 | 4 |
| 31 | Correction of large retardation window effect for ellipsometry measurements using quasi-Newton method. <i>Applied Optics</i> , 2015, 54, 2991. | 1.8 | 4 |
| 32 | Dispersion measurement of the electro-optic coefficient r_{22} of the LiNbO ₃ crystal with Mueller matrix spectropolarimetry. <i>Japanese Journal of Applied Physics</i> , 2015, 54, 078003. | 1.5 | 4 |
| 33 | Selective Cu filling of nanopores using supercritical carbon dioxide. <i>Japanese Journal of Applied Physics</i> , 2015, 54, 05EA02. | 1.5 | 4 |
| 34 | In-situ Spectroscopic Ellipsometry of the Cu Deposition Process from Supercritical Fluids: Evidence of an Abnormal Surface Layer Formation. <i>Japanese Journal of Applied Physics</i> , 2012, 51, 05EA02. | 1.5 | 3 |
| 35 | In situ observation of Pt deposition process by using spectroscopic ellipsometry. <i>Microelectronic Engineering</i> , 2014, 121, 39-41. | 2.4 | 3 |
| 36 | Polarization characteristics of diffraction scattering from metal rough surface. <i>Applied Surface Science</i> , 2017, 421, 565-570. | 6.1 | 3 |

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|----|---|-----|-----------|
| 37 | Optical Absorption and Quantum Confinement in Porous Silicon Nanostructures Studied by Chemical Dissolution in HF Solutions and Photoconduction. ECS Journal of Solid State Science and Technology, 2017, 6, R1-R6. | 1.8 | 3 |
| 38 | Structures of Cu surfaces developing in benzotriazole solutions: Effect of pH. Japanese Journal of Applied Physics, 2017, 56, 07KH01. | 1.5 | 3 |
| 39 | Imaging ellipsometry measurement noises associated with non-uniform retardation of the compensator. Optical Review, 2020, 27, 73-80. | 2.0 | 3 |
| 40 | Image detection system for 157-nm using fluorescent glass. , 2003, , . | | 2 |
| 41 | Birefringence Polarimeter Using Dual LiNbO ₃ Electrooptic Crystal Modulators. Japanese Journal of Applied Physics, 2012, 51, 082201. | 1.5 | 2 |
| 42 | Extraction of polarization properties of the individual components of a layered system by using spectroscopic Mueller matrix analysis. Optics Express, 2016, 24, 9757. | 3.4 | 2 |
| 43 | Removal of organic template of mesoporous organosilicate thin films using supercritical carbon dioxide fluids. Japanese Journal of Applied Physics, 2017, 56, 07KF02. | 1.5 | 2 |
| 44 | Photoetching of Porous Silicon Nanostructures in Hydrofluoric Acid Using Monochromatic Light. ECS Journal of Solid State Science and Technology, 2018, 7, P730-P735. | 1.8 | 2 |
| 45 | Flat-shaped microfluidic optical cell for in situ ellipsometry using glass slide as optical window component. Japanese Journal of Applied Physics, 2018, 57, 07MD01. | 1.5 | 2 |
| 46 | Mueller matrix polarimeter in 157nm. , 2003, 5188, 146. | | 1 |
| 47 | Effect of Multiple Reflections on Accuracy of Electro-Optic Coefficient Measurements. Japanese Journal of Applied Physics, 2007, 46, 7904-7911. | 1.5 | 1 |
| 48 | Tunable electro-optic crystal Fabry-Perot filter. Proceedings of SPIE, 2010, , . | 0.8 | 1 |
| 49 | Polarization analysis of scattering light using a facet model. Proceedings of SPIE, 2011, , . | 0.8 | 1 |
| 50 | Facile and Efficient Gas-Phase Pressure-Controlled Thermal Functionalization of Nanocrystalline Porous Silicon with 1-Hexene. ECS Journal of Solid State Science and Technology, 2019, 8, R109-R113. | 1.8 | 1 |
| 51 | Moire Metrology. , 2009, , . | | 1 |
| 52 | Publisher's Note: "Birefringence Polarimeter Using Dual LiNbO ₃ Electrooptic Crystal Modulators" Japanese Journal of Applied Physics, 0, 51, 089202. | 1.5 | 1 |
| 53 | Characterization of thin films from reflection and transmission ellipsometric parameters. Japanese Journal of Applied Physics, 2022, 61, 018004. | 1.5 | 1 |
| 54 | <title>Shadow moire profilometry using a phase-shifting method</title>. , 1999, 3740, 110. | | 0 |

| # | ARTICLE | IF | CITATIONS |
|----|---|-----|-----------|
| 55 | Measurement of characteristics of magnetic fluid by Mueller matrix imaging polarimeter. , 2002, 4919, 183. | | 0 |
| 56 | Two-dimensional birefringence measurement using liquid crystal retarder for plastic disk inspection. , 2002, , . | | 0 |
| 57 | Development of television camera for detecting oil film floating on the ocean. , 2006, , . | | 0 |
| 58 | Performance of a television camera system for the detection of oil slicks. Optical Engineering, 2008, 47, 093801. | 1.0 | 0 |
| 59 | (Invited) Electropolymerized Poly(para-phenylene)vinylene Films onto and Inside Porous Si. ECS Transactions, 2010, 28, 91-103. | 0.5 | 0 |
| 60 | Analysis of the quadratic retardation induced by the Pockels, Kerr, and inverse piezoelectric effects in anX-cutY-propagation LiNbO ₃ . Japanese Journal of Applied Physics, 2014, 53, 052601. | 1.5 | 0 |
| 61 | (Invited) Porous Silicon Dissolution Monitoring and Optical Constants Measurement Using in Situ Photoconduction in HF. ECS Transactions, 2016, 75, 63-75. | 0.5 | 0 |
| 62 | (Invited) Photo-Assisted Etching of Porous Silicon Nanostructures in Hydrofluoric Acid Using Monochromatic Light. ECS Transactions, 2018, 86, 71-81. | 0.5 | 0 |
| 63 | Birefringence Polarimeter Using Dual LiNbO ₃ Electrooptic Crystal Modulators. Japanese Journal of Applied Physics, 2012, 51, 082201. | 1.5 | 0 |
| 64 | Extraction of properties of individual component for the retarder-linear diattenuator-retarder system and its application. , 2018, , . | | 0 |
| 65 | Dimensional measurement of internal profile using the optical caliper. , 2018, , . | | 0 |
| 66 | Design of a spectroscopic imaging ellipsometer. , 2020, , . | | 0 |
| 67 | Hydrosilylation of High Porosity Porous Silicon with 1-Hexene in Supercritical CO ₂ Fluid. ECS Journal of Solid State Science and Technology, 0, , . | 1.8 | 0 |
| 68 | 3D profile measurement of openings with optical caliper. , 2021, , . | | 0 |
| 69 | Ellipsometric Microscope •Design and Application of a Microscope for Oblique Observation of Samples•. Journal of the Japan Society for Precision Engineering, 2020, 86, 533-536. | 0.1 | 0 |
| 70 | Optical profilometry of cylindrical openings for transparent objects. , 2020, , . | | 0 |
| 71 | High Energy Limit of the Size-Tunable Photoluminescence of Hydrogen-Terminated Porous Silicon Nanostructures in HF. ECS Journal of Solid State Science and Technology, 0, , . | 1.8 | 0 |
| 72 | Electron Escape from Filled Band in Wet Porous Silicon Nanostructure Probed by Luminescence Quenching Dynamics. ECS Journal of Solid State Science and Technology, 0, , . | 1.8 | 0 |